



Static & Dynamic Module Tester



- Static test
- Heating up
- Dynamic test at $\leq 180^{\circ}\text{C}$
- Cooling down
- Second static test

Static & Dynamic DCB Tester

The module tester from MicroContact covers the complete high current test. After the first static test, the modules are heated to the required test temperature and will be tested dynamically. After a cooling phase, the modules are statically tested a second time and the test results are compared.

System description:

- Static test
- Heating up to $\leq 180^{\circ}\text{C}$
- Dynamic test from top or from both side
- Cooling down to $< 30^{\circ}\text{C}$
- Second static test
- System cycle time ≥ 60 seconds
- Module dimension up to 210mm x 110mm x 40mm

Test definitions for VX Instruments:

Static test:

- Up to 3'000V, 3'000A
- Pulse $> 100\mu\text{s}$
- Wide Bandgap testing (Si, SiC, GaN)
- MOSFET's, IGBT's
- RDS(ON)
- VBRSS, IDSS, IGSS
- VGSTH
- VSD
- ...

Dynamic test:

- Up to 1'500V, 10'000A, pulse $> 0.5\mu\text{s}$
- Multipulse test
- Short circuit test
- UIS (unclamped inductive switching)
- CIS (clamped inductive switching)